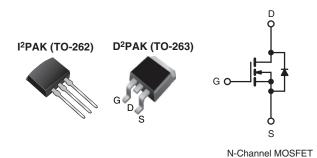


Vishay Siliconix

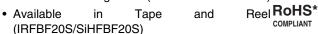
## **Power MOSFET**

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	900			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V 8.0			
Q <sub>g</sub> (Max.) (nC)	38			
Q <sub>gs</sub> (nC)	4.7			
Q <sub>gd</sub> (nC)	21			
Configuration	Single			



#### **FEATURES**

- Surface Mount (IRFBF20S/SiHFBF20S)
- Low-Profile Through-Hole (IRFBF20L/SiHFBF20L)



- · Dynamic dV/dt Rating
- 150 °C Operating Temperature
- · Fast Switching
- · Fully Avalanche Rated
- Lead (Pb)-free Available

#### **DESCRIPTION**

Third generation Power MOSFETs form Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The D<sup>2</sup>PAK is a surface mount power package capabel of the accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D<sup>2</sup>PAK is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application. The through-hole version (IRFBF20L/SiHFBF20L) is available for low-profile applications.

ORDERING INFORMATION						
Package	D <sup>2</sup> PAK (TO-263)	D <sup>2</sup> PAK (TO-263)	D <sup>2</sup> PAK (TO-263)	I <sup>2</sup> PAK (TO-262)		
Lead (Pb)-free	IRFBF20SPbF	IRFBF20STRLPbFa	IRFBF20STRRPbFa	IRFBF20LPbF		
	SiHFBF20S-E3	SiHFBF20STL-E3a	SiHFBF20STR-E3a	SiHFBF20L-E3		
SnPb	IRFBF20S	IRFBF20STRL <sup>a</sup>	IRFBF20STRRa	IRFBF20L		
SNPD	SiHFBF20S-E3	SiHFBF20STL <sup>a</sup>	SiHFBF20STR <sup>a</sup>	SiHFBF20L		

#### Note

a. See device orientation.

ABSOLUTE MAXIMUM RATI	<b>NGS</b> T <sub>C</sub> = 25 °C,	unless otherv	vise noted		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage <sup>e</sup>			V <sub>DS</sub>	900	V
Gate-Source Voltagee			V <sub>GS</sub>	± 20	v
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$	I-	1.7	
Continuous Drain Current	V <sub>GS</sub> at 10 v	T <sub>C</sub> = 100 °C	l <sub>D</sub>	1.1	Α
Pulsed Drain Current <sup>a,e</sup>			I <sub>DM</sub>	6.8	
Linear Derating Factor				0.43	W/°C
Single Pulse Avalanche Energy <sup>b, e</sup>			E <sub>AS</sub>	180	mJ
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	1.7	Α
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	5.4	mJ
Maximum Dawar Dissination	T <sub>C</sub>	T <sub>C</sub> = 25 °C T <sub>A</sub> = 25 °C		54	w
Maximum Power Dissipation	T <sub>A</sub>			3.1	vv
Peak Diode Recovery dV/dtc, e		dV/dt	1.5	V/ns	

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply

# IRFBF20S, IRFBF20L, SiHFBF20S, SiHFBF20L

# Vishay Siliconix



ABSOLUTE MAXIMUM RATINGS T <sub>C</sub> = 25 °C, unless otherwise noted						
PARAMETER	SYMBOL	LIMIT	UNIT			
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>	O		
Mounting Torque	6-32 or M3 screw		10	N		

#### **Notes**

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 50$  V; starting  $T_J = 25$  °C, L = 117 mH,  $R_G = 25$   $\Omega$ ,  $I_{AS} = 1.7$  A (see fig. 12). c.  $I_{SD} \le 1.7$  A,  $I_{AS} = 1.7$  A,  $I_{AS} = 1.7$  A (see fig. 12). d.  $I_{AS} = 1.7$  A (see fig. 12).

- e. Uses IRFBF20/SiHFBF20 data and test conditions.

THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient (PCB Mounted, steady-state) <sup>a</sup>	R <sub>thJA</sub>	-	40	°C/W		
Maximum Junction-to-Case	R <sub>thJC</sub>	-	2.3			

#### Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

<b>SPECIFICATIONS</b> T <sub>J</sub> = 25 °C, unless otherwise noted								
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 250 μA	900	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	ce to 25 °C, I <sub>D</sub> = 1 mA	-	1.1	-	mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	,	V <sub>GS</sub> = ± 20 V	-	-	± 100	nA	
Zanz Oaks Wallana Busin Oamani		V <sub>DS</sub> =	900 V, V <sub>GS</sub> = 0 V	-	-	100	μΑ	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 720 V	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	500		
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 1.0 A <sup>b</sup>	-	-	8.0	Ω	
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 1.0 A <sup>b</sup>		0.6	-	-	S	
Dynamic		•						
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V,		-	490	-	pF	
Output Capacitance	C <sub>oss</sub>			-	55	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.	f = 1.0 MHz, see fig. 5		18	-		
Total Gate Charge	Qg			-	-	38		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$I_D = 1.7 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and $13^b$	-	-	4.7	nC	
Gate-Drain Charge	Q <sub>gd</sub>			-	-	21		
Turn-On Delay Time	t <sub>d(on)</sub>			-	8.0	-		
Rise Time	t <sub>r</sub>	$V_{DD} = 450 \text{ V}, I_{D} = 1.7 \text{ A},$ $R_{G} = 18 \Omega, V_{GS} = 10 \text{ V}, \text{ see fig. } 10^{b}$		-	21	-		
Turn-Off Delay Time	t <sub>d(off)</sub>			-	56	-	ns ns	
Fall Time	t <sub>f</sub>			-	32	-		

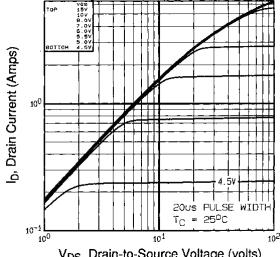
Vishay Siliconix

<b>SPECIFICATIONS</b> T <sub>J</sub> = 25 °C, unless otherwise noted							
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the	-	-	1.7	А	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode	-	-	6.8	_ ^	
Body Diode Voltage	$V_{SD}$	$T_J = 25  ^{\circ}\text{C}, \ I_S = 1.7  \text{A}, \ V_{GS} = 0  \text{V}^{\text{b}}$	-	-	1.5	٧	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 1.7 A, dl/dt = 100 A/μs <sup>b</sup>	-	350	530	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$I_{J} = 25$ C, $I_{F} = 1.7$ A, $I_{A} = 100$ A/ $I_{A} = 100$	-	0.85	1.3	μC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )					

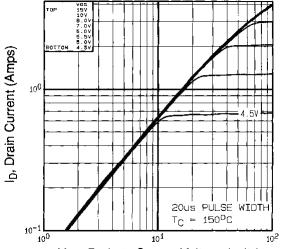
#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %.
- c. Uses IRFBF20/SiHFBF20 data and test conditions.

#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



V<sub>DS</sub>, Drain-to-Source Voltage (volts) Fig. 1 - Typical Output Characteristics

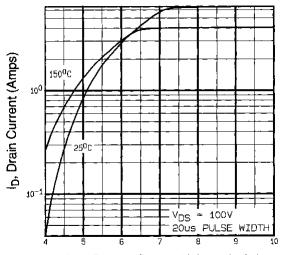


V<sub>DS</sub>, Drain-to-Source Voltage (volts) Fig. 2 - Typical Output Characteristics

## IRFBF20S, IRFBF20L, SiHFBF20S, SiHFBF20L

## Vishay Siliconix





V<sub>GS</sub>, Gate-to-Source Voltage (volts) Fig. 3 - Typical Transfer Characteristics

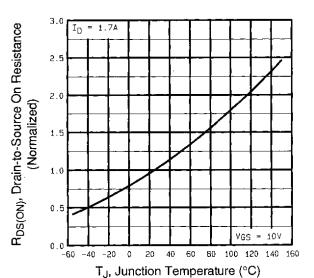


Fig. 4 - Normalized On-Resistance vs. Temperature

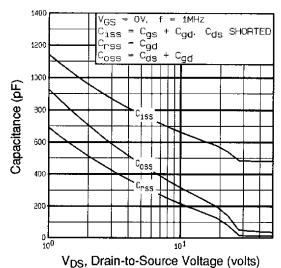


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

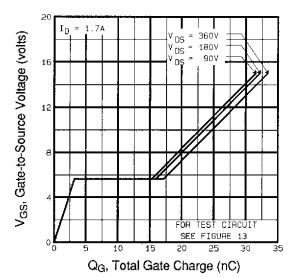


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



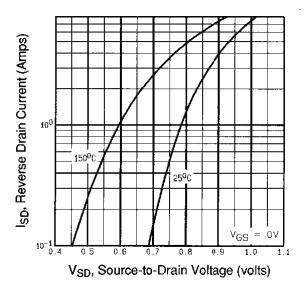


Fig. 7 - Typical Source-Drain Diode Forward Voltage

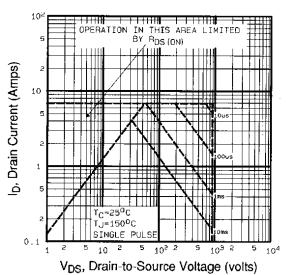


Fig. 8 - Maximum Safe Operating Area

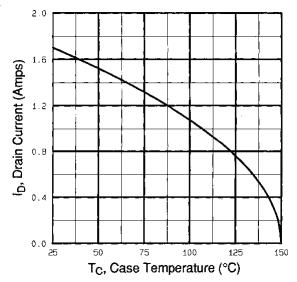


Fig. 9 - Maximum Drain Current vs. Case Temperature

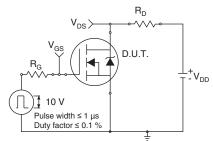


Fig. 10a - Switching Time Test Circuit

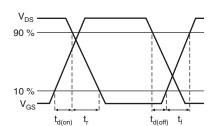


Fig. 10b - Switching Time Waveforms

# IRFBF20S, IRFBF20L, SiHFBF20S, SiHFBF20L

## Vishay Siliconix



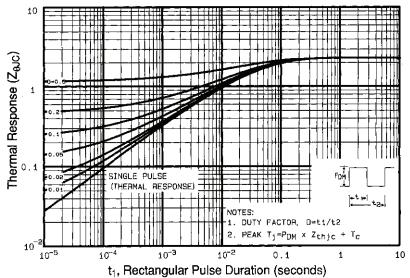


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

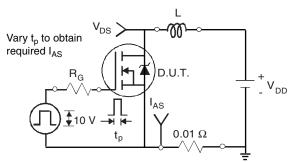


Fig. 12a - Unclamped Inductive Test Circuit

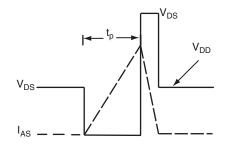


Fig. 12b - Unclamped Inductive Waveforms

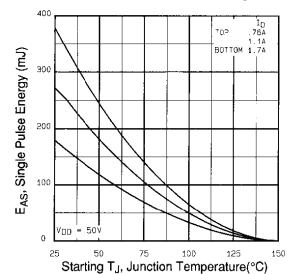


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

## Vishay Siliconix

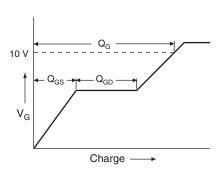


Fig. 13a - Basic Gate Charge Waveform

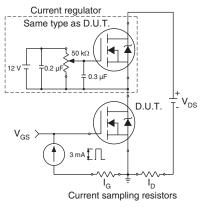
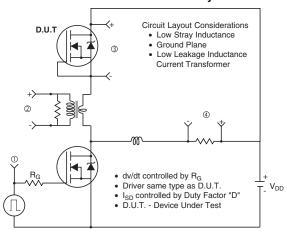


Fig. 13b - Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit



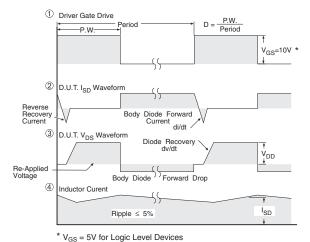


Fig. 14 - For N-Channel

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?91121.



Vishay

## **Disclaimer**

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.

Document Number: 91000 Revision: 18-Jul-08